# HM628128A Series

**131,072-word × 8-bit High Speed CMOS Static RAM**

The Hitachi HM628128A is a CMOS static RAM organized 128 kword × 8 bit. It realizes higher density, higher performance and low power consumption by employing 0.8 µm Hi-CMOS process technology.

It offers low power standby power dissipation; therefore, it is suitable for battery back-up systems. The device, packaged in a 525-mil SOP (460-mil body SOP) or a 600-mil plastic DIP, or a 8 × 20 mm TSOP with thickness of 1.2 mm, is available for high density mounting. TSOP package is suitable for cards, and reverse type TSOP is also provided.

## Features

- High speed
  - Fast access time: 55/70/85/100 ns (max)
- Low power
  - Active: 75 mW (typ)
  - Standby: 10 µW (typ) (L/L-L/L-SL version)
- Single 5 V supply
- Completely static memory
  - No clock or timing strobe required
- Equal access and cycle times
- Common data input and output
  - Three state output
- Directly TTL compatible
  - All inputs and outputs
- Capability of battery back up operation (L/L-L/L-SL version)
  - 2 chip selection for battery back up

## Ordering Information

| Type No. | Access time | Package |
|---|---|---|
| HM628128ALP–5 | 55 ns | 600-mil 32-pin plastic DIP (DP-32) |
| HM628128ALP–7 | 70 ns | |
| HM628128ALP–8 | 85 ns | |
| HM628128ALP–10 | 100 ns | |
| HM628128ALP–5L | 55 ns | |
| HM628128ALP–7L | 70 ns | |
| HM628128ALP–8L | 85 ns | |
| HM628128ALP–10L | 100 ns | |
| HM628128ALFP–5 | 55 ns | 525-mil 32-pin plastic SOP (FP-32D) |
| HM628128ALFP–7 | 70 ns | |
| HM628128ALFP–8 | 85 ns | |
| HM628128ALFP–10 | 100 ns | |
| HM628128ALFP–5L | 55 ns | |
| HM628128ALFP–7L | 70 ns | |
| HM628128ALFP–8L | 85 ns | |
| HM628128ALFP–10L | 100 ns | |
| HM628128ALFP–5SL | 55 ns | |
| HM628128ALFP–7SL | 70 ns | |
| HM628128ALFP–8SL | 85 ns | |
| HM628128ALFP–10SL | 100 ns | |
| HM628128ALT–5 | 55 ns | 8 mm × 20 mm 32-pin TSOP (normal type) (TFP-32D) |
| HM628128ALT–7 | 70 ns | |
| HM628128ALT–8 | 85 ns | |
| HM628128ALT–10 | 100 ns | |
| HM628128ALT–5L | 55 ns | |
| HM628128ALT–7L | 70 ns | |
| HM628128ALT–8L | 85 ns | |
| HM628128ALT–10L | 100 ns | |
| HM628128ALR–5 | 55 ns | 8 mm × 20 mm 32-pin TSOP (reverse type) (TFP-32DR) |
| HM628128ALR–7 | 70 ns | |
| HM628128ALR–8 | 85 ns | |
| HM628128ALR–10 | 100 ns | |
| HM628128ALR–5L | 55 ns | |
| HM628128ALR–7L | 70 ns | |
| HM628128ALR–8L | 85 ns | |
| HM628128ALR–10L | 100 ns | |

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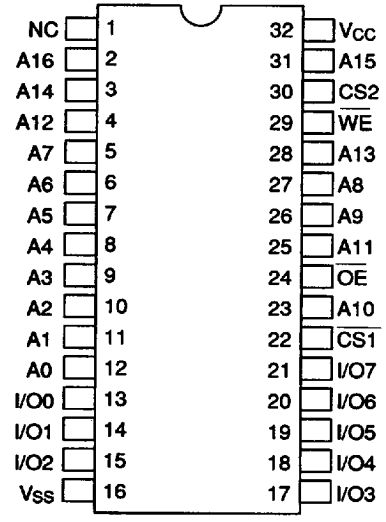
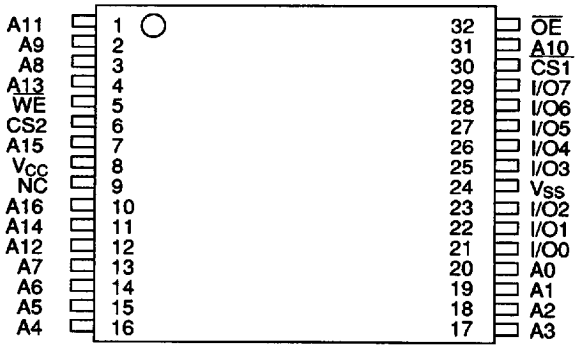
## Pin Arrangement

HM628128ALP/ALFP Series



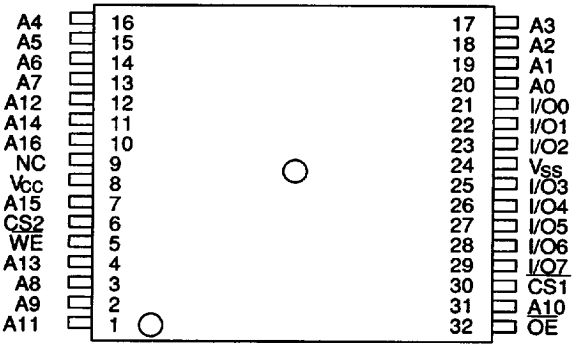

(Top View)

HM628128ALT Series




(Top View)

HM628128ALR Series

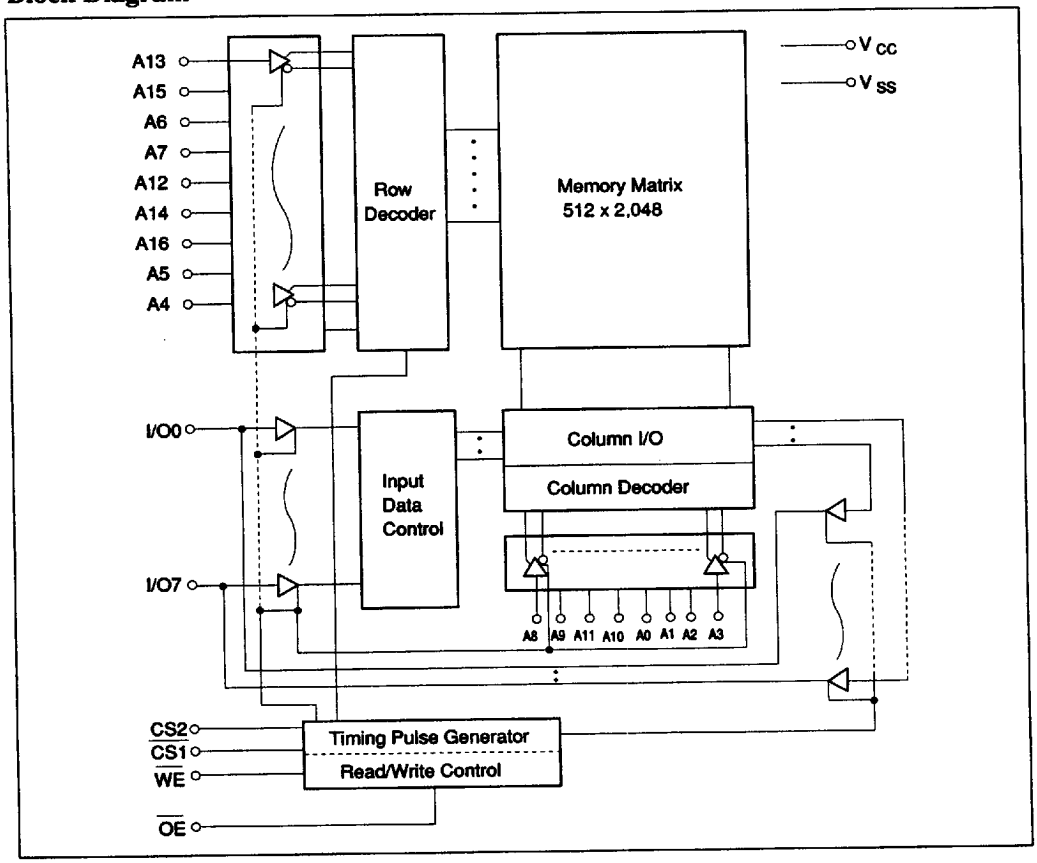



(Top View)

## Pin Description

| Pin name | Function |
|---|---|
| A0 – A16 | Address |
| I/O0 – I/O7 | Input/output |
| $\overline{CS1}$ | Chip select 1 |
| CS2 | Chip select 2 |
| $\overline{WE}$ | Write enable |
| $\overline{OE}$ | Output enable |
| NC | No connection |
| $V_{CC}$ | Power supply |
| $V_{SS}$ | Ground |

## Block Diagram




## Absolute Maximum Ratings

| Parameter | Symbol | Value | Unit |
|---|---|---|---|
| Supply voltage relative to $V_{SS}$ | $V_{CC}$ | –0.5 to +7.0 | V |
| Voltage on any pin relative to $V_{SS}$ | $V_T$ | –0.5 *1 to $V_{CC}$ + 0.3*2 | V |
| Power dissipation | $P_T$ | 1.0 | W |
| Operating temperature | Topr | 0 to +70 | °C |
| Storage temperature | Tstg | –55 to +125 | °C |
| Storage temperature under bias | Tbias | –10 to +85 | °C |

Note: 1. –3.0 V for pulse half-width ≤ 30 ns
2. Maximum voltage is 7.0V.

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## Function Table

| $\overline{CS1}$ | CS2 | $\overline{OE}$ | $\overline{WE}$ | Mode | $V_{CC}$ current | I/O pin | Ref. cycle |
|---|---|---|---|---|---|---|---|
| H | X | X | X | Standby | $I_{SB}$, $I_{SB1}$ | High-Z | — |
| X | L | X | X | Standby | $I_{SB}$, $I_{SB1}$ | High-Z | — |
| L | H | H | H | Output disable | $I_{CC}$ | High-Z | — |
| L | H | L | H | Read | $I_{CC}$ | Dout | Read cycle |
| L | H | H | L | Write | $I_{CC}$ | Din | Write cycle (1) |
| L | H | L | L | Write | $I_{CC}$ | Din | Write cycle (2) |

Note: 1. X: H or L

## Recommended DC Operating Conditions (Ta = 0 to +70°C)

| Parameter | Symbol | Min | Typ | Max | Unit |
|---|---|---|---|---|---|
| Supply voltage | $V_{CC}$ | 4.5 | 5.0 | 5.5 | V |
| | $V_{SS}$ | 0 | 0 | 0 | V |
| Input voltage (HM628128A-7/8/10) | $V_{IH}$ | 2.2 | — | $V_{CC}$ + 0.3 | V |
| | $V_{IL}$ | –0.3 *1 | — | 0.8 | V |
| Input voltage (HM628128A-5) | $V_{IH}$ | 2.4 | — | $V_{CC}$ + 0.3 | V |
| | $V_{IL}$ | –0.3 *1 | — | 0.8 | V |

Note: 1. –3.0 V for pulse half-width ≤ 30 ns

## DC Characteristics (Ta = 0 to +70°C, $V_{CC}$ = 5 V ± 10%, $V_{SS}$ = 0 V)

| Parameter | Symbol | Min | Typ*1 | Max | Unit | Test conditions | Notes |
|---|---|---|---|---|---|---|---|
| Input leakage current | $\|I_{LI}\|$ | — | — | 1.0 | µA | Vin = $V_{SS}$ to $V_{CC}$ | |
| Output leakage current | $\|I_{LO}\|$ | — | — | 1.0 | µA | $\overline{CS1}$ = $V_{IH}$ or CS2 = $V_{IL}$ or $\overline{OE}$ = $V_{IH}$ or $\overline{WE}$ = $V_{IL}$, $V_{I/O}$ = $V_{SS}$ to $V_{CC}$ | |
| Operating power supply current: DC | $I_{CC}$ | — | 15 | 30 | mA | $\overline{CS1}$ = $V_{IL}$, CS2 = $V_{IH}$, Others = $V_{IH}$/$V_{IL}$, $I_{I/O}$ = 0 mA | |
| Operating power supply current | $I_{CC1}$ | — | 45 | 70 | mA | Min cycle, duty = 100%, $\overline{CS1}$ = $V_{IL}$, CS2 = $V_{IH}$, Others = $V_{IH}$/$V_{IL}$, $I_{I/O}$ = 0 mA | HM628128A -7/8/10 |
| | | — | 50 | 80 | mA | | HM628128A -5 |
| | $I_{CC2}$ | — | 15 | 25 | mA | Cycle time = 1 µs, duty = 100%, $I_{I/O}$ = 0 mA, $\overline{CS1}$ ≤ 0.2 V, CS2 > VCC − 0.2 V, $V_{IH}$ ≥ $V_{CC}$ − 0.2 V, $V_{IL}$ ≤ 0.2 V | |
| Standby power supply current: DC | $I_{SB}$ | — | 1 | 2 | mA | $\overline{CS1}$ = $V_{IH}$, CS2 = $V_{IH}$ or CS2 = $V_{IL}$ | |
| Standby power supply current (1): DC | $I_{SB1}$ | — | 0.02 | 2 | mA | 0 V ≤ Vin ≤ $V_{CC}$, $\overline{CS1}$ ≥ $V_{CC}$ − 0.2 V, CS2 ≥ $V_{CC}$ − 0.2 V or 0 V ≤ CS2 ≤ 0.2 V | |
| | | — | 2 | 100 | µA | | L-version |
| | | — | 2 | 50 | µA | | L-L/L-SL version |
| Output voltage | $V_{OL}$ | — | — | 0.4 | V | $I_{OL}$ = 2.1 mA | |
| | $V_{OH}$ | 2.4 | — | — | V | $I_{OH}$ = −1.0 mA | |

Note: 1. Typical values are at $V_{CC}$ = 5.0 V, Ta = +25°C and specified loading.

## Capacitance (Ta = 25°C, f = 1.0 MHz)*1

| Parameter | Symbol | Min | Typ | Max | Unit | Test conditions |
|---|---|---|---|---|---|---|
| Input capacitance | Cin | — | — | 8 | pF | Vin = 0 V |
| Input/output capacitance | $C_{I/O}$ | — | — | 10 | pF | $V_{I/O}$ = 0 V |

Note: 1. This parameter is sampled and not 100% tested.

## AC Characteristics (Ta = 0 to +70°C, $V_{CC}$ = 5 V ± 10%, unless otherwise noted.)

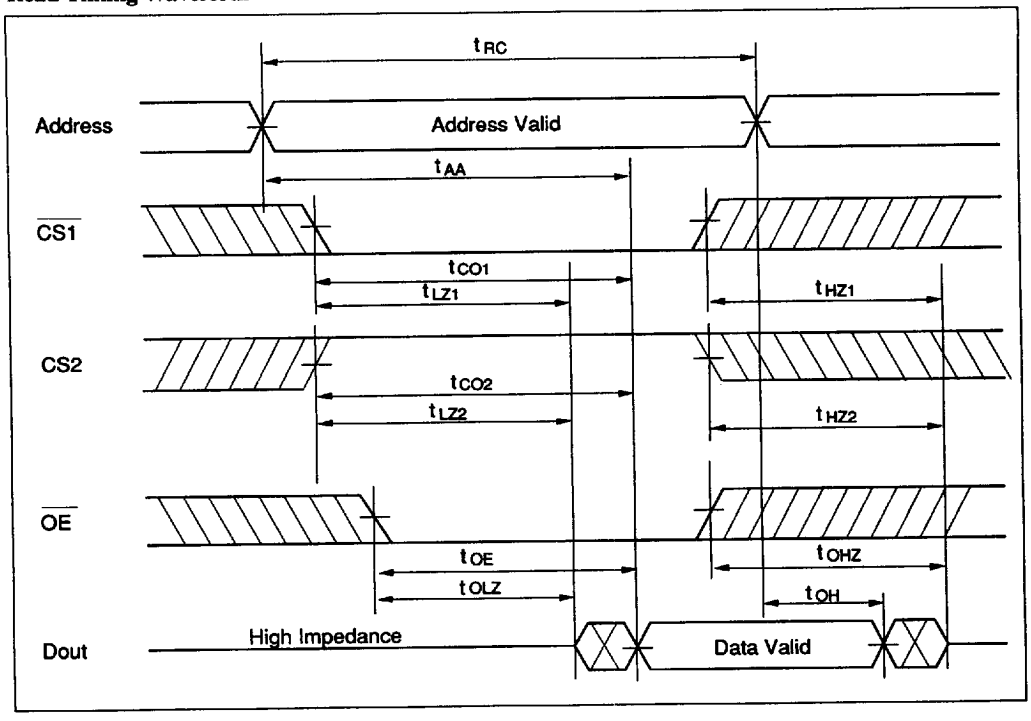
### Test Conditions

- Input pulse levels: 0.8 V to 2.4 V (HM628128A-7/8/10)
  0 V to 3 V (HM628128A-5)
- Input rise and fall times: 5 ns
- Input and output timing reference levels: 1.5 V
- Output load: 1 TTL Gate and CL (100 pF) (HM628128A-7/8/10)
  1 TTL Gate and CL (30 pF) (HM628128A-5)
  (Including scope & jig)

### Read Cycle

| | | HM628128A | | | | | | | | | |
|---|---|---|---|---|---|---|---|---|---|---|---|
| | | -5 | | -7 | | -8 | | -10 | | | |
| Parameter | Symbol | Min | Max | Min | Max | Min | Max | Min | Max | Unit | Notes |
| Read cycle time | $t_{RC}$ | 55 | — | 70 | — | 85 | — | 100 | — | ns | |
| Address access time | $t_{AA}$ | — | 55 | — | 70 | — | 85 | — | 100 | ns | |
| Chip selection to output valid | $t_{CO1}$ | — | 55 | — | 70 | — | 85 | — | 100 | ns | |
| | $t_{CO2}$ | — | 55 | — | 70 | — | 85 | — | 100 | ns | |
| Output enable to output valid | $t_{OE}$ | — | 30 | — | 35 | — | 45 | — | 50 | ns | |
| Chip selection to output in low-Z | $t_{LZ1}$ | 5 | — | 10 | — | 10 | — | 10 | — | ns | 1, 2, 3 |
| | $t_{LZ2}$ | 5 | — | 10 | — | 10 | — | 10 | — | ns | 1, 2, 3 |
| Output enable to output in low-Z | $t_{OLZ}$ | 5 | — | 5 | — | 5 | — | 5 | — | ns | 1, 2, 3 |
| Chip deselection to output in high-Z | $t_{HZ1}$ | 0 | 20 | 0 | 25 | 0 | 30 | 0 | 35 | ns | 1, 2, 3 |
| | $t_{HZ2}$ | 0 | 20 | 0 | 25 | 0 | 30 | 0 | 35 | ns | 1, 2, 3 |
| Output disable to output in high-Z | $t_{OHZ}$ | 0 | 20 | 0 | 25 | 0 | 30 | 0 | 35 | ns | 1, 2, 3 |
| Output hold from address change | $t_{OH}$ | 5 | — | 10 | — | 10 | — | 10 | — | ns | |

**Read Timing Waveform** *4




Notes:
1. $t_{HZ}$ and $t_{OHZ}$ are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.
2. At any given temperature and voltage condition, $t_{HZ}$ max is less than $t_{LZ}$ min both for a given device and from device to device.
3. This parameter is sampled and not 100% tested.
4. $\overline{WE}$ is high for read cycle.

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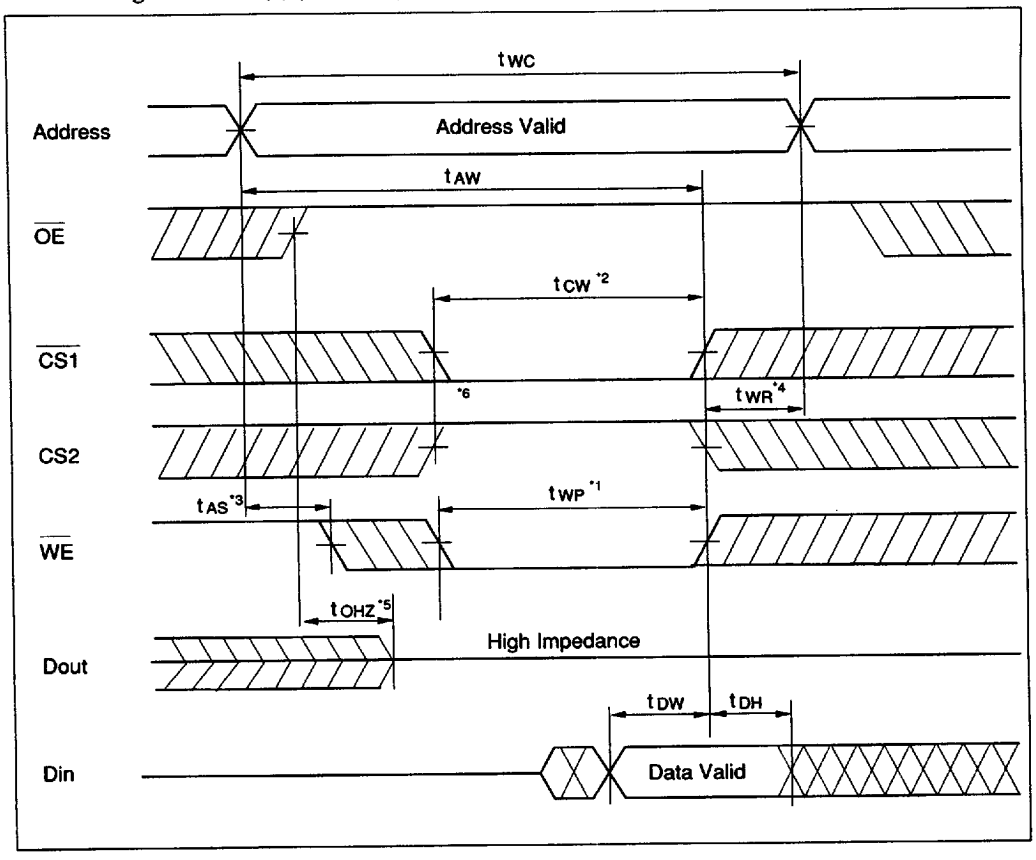
## Write Cycle

| | | HM628128A | | | | | | | | | |
|---|---|---|---|---|---|---|---|---|---|---|---|
| | | -5 | | -7 | | -8 | | -10 | | | |
| Parameter | Symbol | Min | Max | Min | Max | Min | Max | Min | Max | Unit | Notes |
| Write cycle time | $t_{WC}$ | 55 | — | 70 | — | 85 | — | 100 | — | ns | |
| Chip selection to end of write | $t_{CW}$ | 50 | — | 60 | — | 75 | — | 80 | — | ns | |
| Address setup time | $t_{AS}$ | 0 | — | 0 | — | 0 | — | 0 | — | ns | |
| Address valid to end of write | $t_{AW}$ | 50 | — | 60 | — | 75 | — | 80 | — | ns | |
| Write pulse width | $t_{WP}$ | 40 | — | 50 | — | 55 | — | 60 | — | ns | |
| Write recovery time | $t_{WR}$ | 0 | — | 0 | — | 0 | — | 0 | — | ns | |
| | | 0 | — | 0 | — | 0 | — | 0 | — | ns | 11 |
| Write to output in high-Z | $t_{WHZ}$ | 0 | 20 | 0 | 25 | 0 | 30 | 0 | 35 | ns | 10 |
| Data to write time overlap | $t_{DW}$ | 25 | — | 30 | — | 35 | — | 40 | — | ns | |
| Data hold from write time | $t_{DH}$ | 0 | — | 0 | — | 0 | — | 0 | — | ns | |
| Output active from end of write | $t_{OW}$ | 5 | — | 5 | — | 5 | — | 5 | — | ns | 10 |

**Write Timing Waveform (1) ($\overline{OE}$ Clock)**

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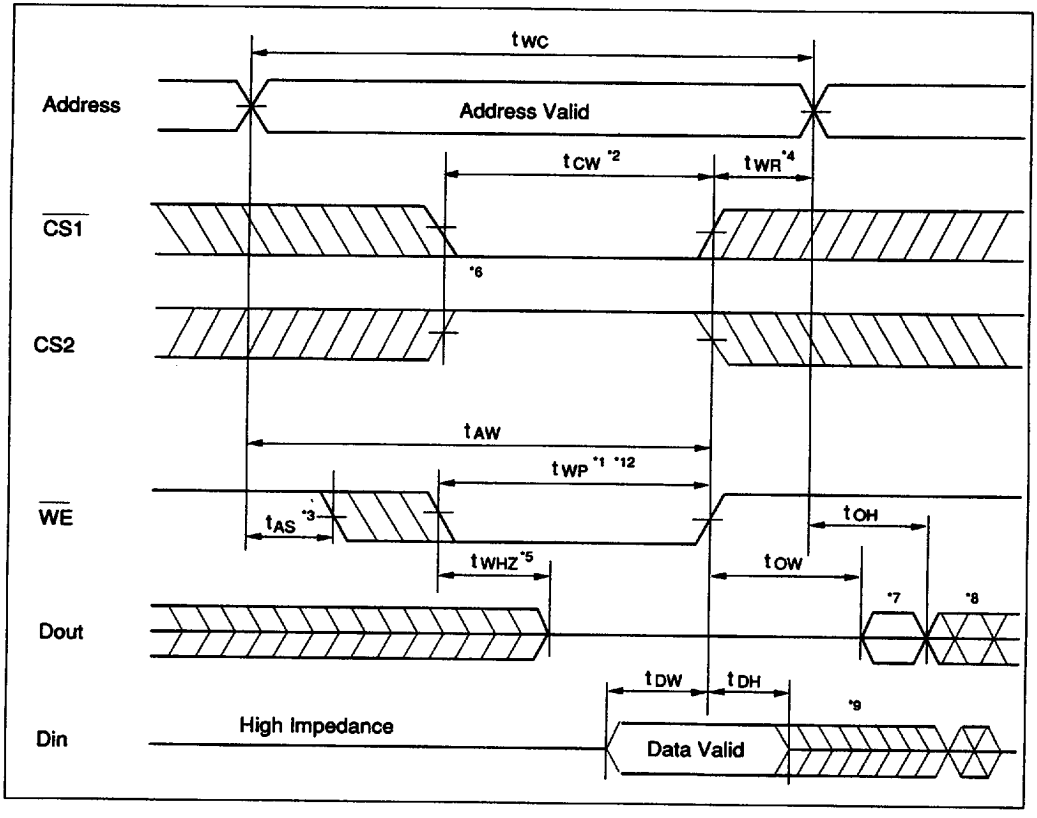
**Write Timing Waveform (2) ($\overline{OE}$ low Fixed)**



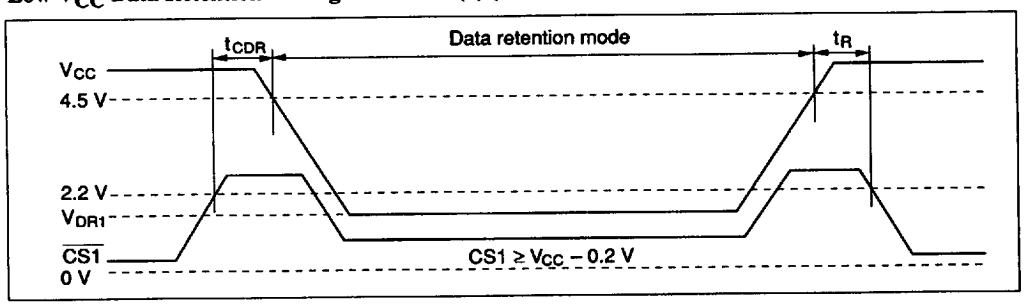

Notes:
1. A write occurs during the overlap of a low $\overline{CS1}$, a high CS2, and a low $\overline{WE}$. A write begins at the latest transition among $\overline{CS1}$ going low, CS2 going high, and $\overline{WE}$ going low. A write ends at the earliest transition among $\overline{CS1}$ going high, CS2 going low, and $\overline{WE}$ going high. $t_{WP}$ is measured from the beginning of write to the end of write.
2. $t_{CW}$ is measured from the later of $\overline{CS1}$ going low or CS2 going high to the end of write.
3. $t_{AS}$ is measured from the address valid to the beginning of write.
4. $t_{WR}$ is measured from the earliest of $\overline{CS1}$ or $\overline{WE}$ going high or CS2 going low to the end of write cycle.
5. During this period, I/O pins are in the output state; therefore, the input signals of the opposite phase to the outputs must not be applied.
6. If the $\overline{CS1}$ goes low simultaneously with $\overline{WE}$ going low or after the $\overline{WE}$ going low, the outputs remain in a high impedance state.
7. Dout is the same phase of the latest written data in this write cycle.
8. Dout is the read data of next address.
9. If $\overline{CS1}$ is low and CS2 high during this period, I/O pins are in the output state. Therefore, the input signals of opposite phase to the outputs must not be applied to them.
10. This parameter is sampled and not 100% tested.
11. This value is measured from CS2 going low to the end of write cycle.
12. In the write cycle with $\overline{OE}$ low fixed, $t_{WP}$ must satisfy the following equation to avoid a problem of data bus contention.
    $t_{WP} \geq t_{DW}$ min + $t_{WHZ}$ max

## Low $V_{CC}$ Data Retention Characteristics (Ta = 0 to +70°C)

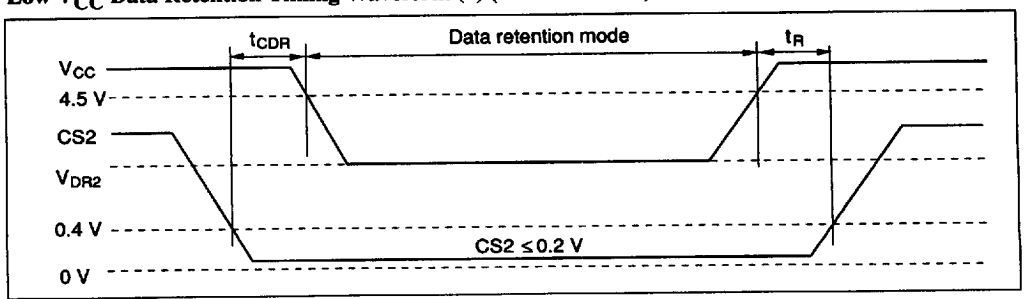
This characteristics is guaranteed only for L, L-L, and L-SL version.

| Parameter | Symbol | Min | Typ | Max | Unit | Test conditions | Notes |
|---|---|---|---|---|---|---|---|
| $V_{CC}$ for data retention | $V_{DR}$ | 2.0 | — | — | V | $\overline{CS1} \geq V_{CC} - 0.2$ V, $CS2 \geq V_{CC} - 0.2$ V or $0\text{ V} \leq CS2 \leq 0.2$ V, $Vin \geq 0$ V | |
| Data retention current | $I_{CCDR}$ | — | 1 | 50*1 | µA | $V_{CC}$ = 3.0 V, $Vin \geq 0$ V, $\overline{CS1} \geq V_{CC} - 0.2$V | L version |
| | | — | 1 | 30*2 | µA | $CS2 \geq V_{CC} - 0.2$ V or $0\text{ V} \leq CS2 \leq 0.2$ V | L-L version |
| | | — | 1 | 15*3 | µA | | L-SL version |
| Chip deselect to data retention time | $t_{CDR}$ | 0 | — | — | ns | See retention waveform | |
| Operation recovery time | $t_R$ | 5 | — | — | ms | | |

### Low $V_{CC}$ Data Retention Timing Waveform (1) ($\overline{CS1}$ Controlled)




### Low $V_{CC}$ Data Retention Timing Waveform (2) (CS2 Controlled)




Notes: 1. 20 µA max at Ta = 0 to 40°C (L version).
2. 6 µA max at Ta = 0 to 40°C (L-L version).
3. 3 µA max at Ta = 0 to 40°C (L-SL version).
4. CS2 controls address buffer, $\overline{WE}$ buffer, $\overline{CS1}$ buffer, $\overline{OE}$ buffer, and Din buffer. If CS2 controls data retention mode, Vin levels (address, $\overline{WE}$, $\overline{OE}$, $\overline{CS1}$, I/O) can be in the high impedance state. If $\overline{CS1}$ controls data retention mode, CS2 must be $CS2 \geq V_{CC} - 0.2$ V or $0\text{ V} \leq CS2 \leq 0.2$ V. The other input levels (address, $\overline{WE}$, $\overline{OE}$, I/O) can be in the high impedance state.